HIGH-GRADIENT TESTING OF X-BAND SINGLE CELL TEST STRUCTURES AT KEK/NEXTEF

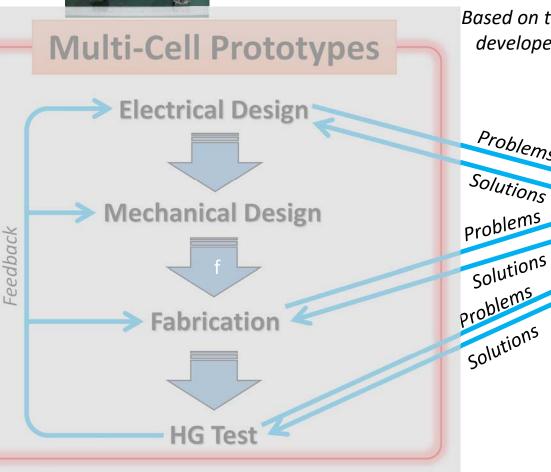
Tetsuo ABE (KEK)

on behalf of Nextef team

LCWS2016 @ MORIOKA, IWATE, Japan 2016-12-08



Research Strategy



✓ Comprehensive study and development

Based on the NC X-band technology developed by SLAC-CERN-KEK collaboration

Covered by this talk

Problems Solutions problems Solutions problems

Single-Cell Cavities

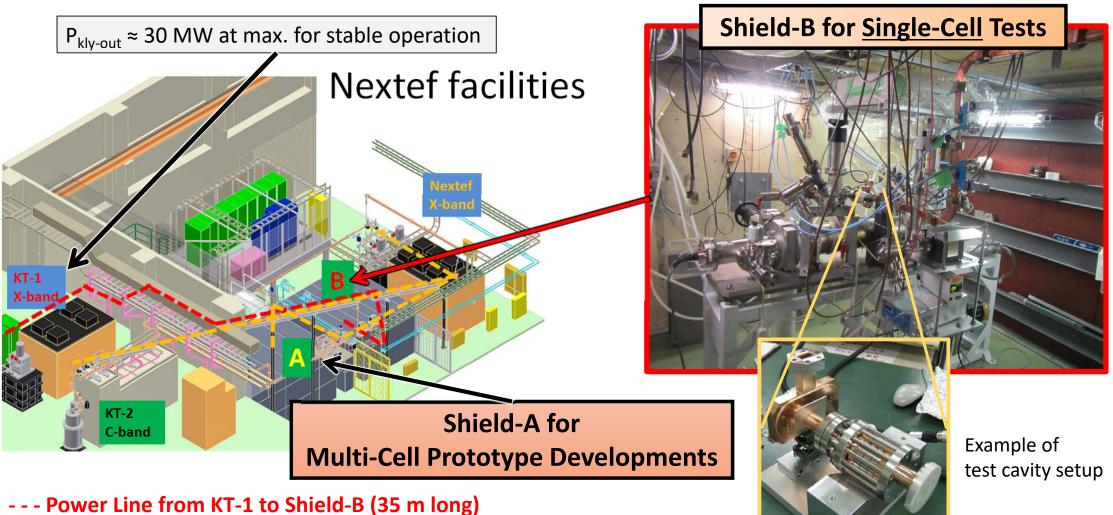
Design → **Fabrication** → **HG Test**

- ✓ Minimum structure keeping realistic RF fields for acceleration
- ✓ Palm-sized cavity
- ✓ Basic study, element test
- ✓ Easy to make and test

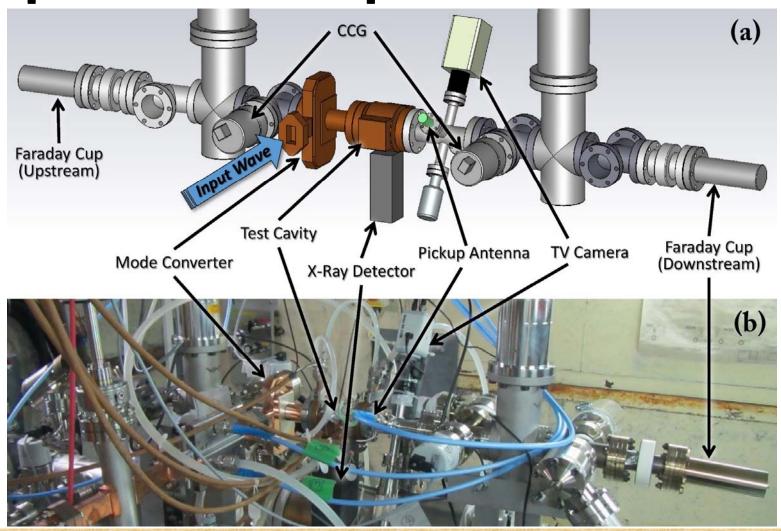
V. A. Dolgashev, S. G. Tantawi, C. D. Nantista, Y. Higashi, and T. Higo, "Travelling wave and standing wave single cell high gradient tests," SLAC-PUB-10667, 2004.

✓ Cost and time consuming

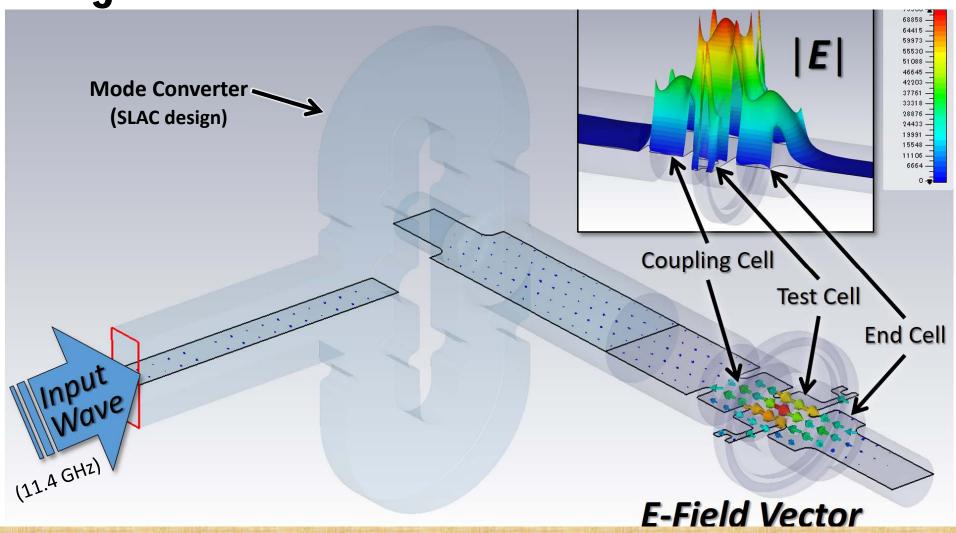
KEK / Nextef for X-Band Accelerating Structure Developments

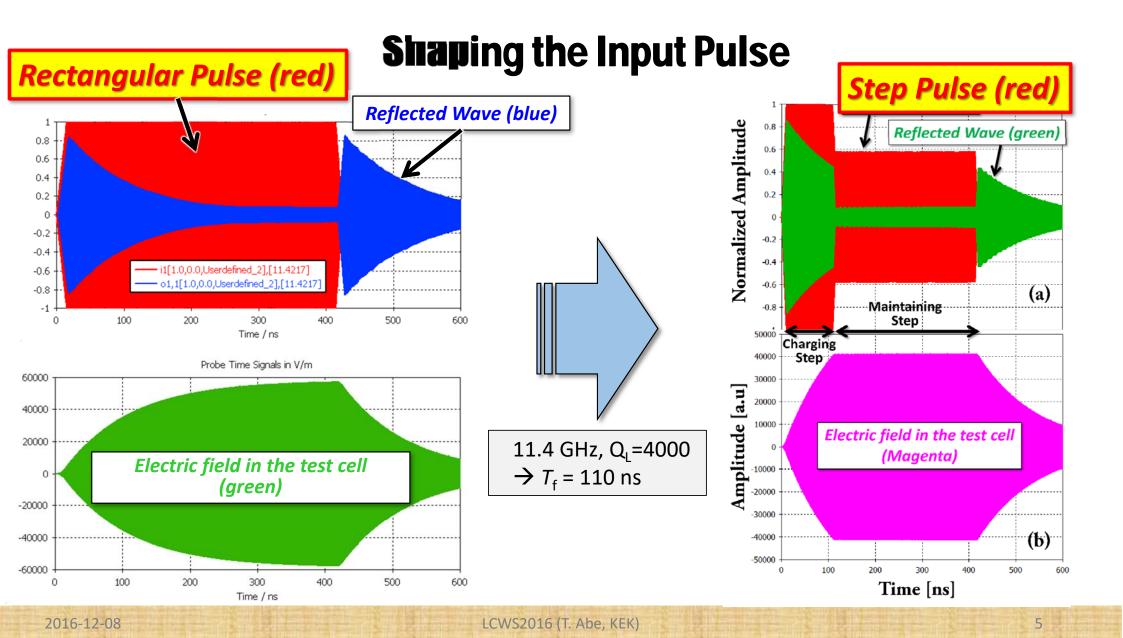


Experimental Setup of Nextef / Shield-B

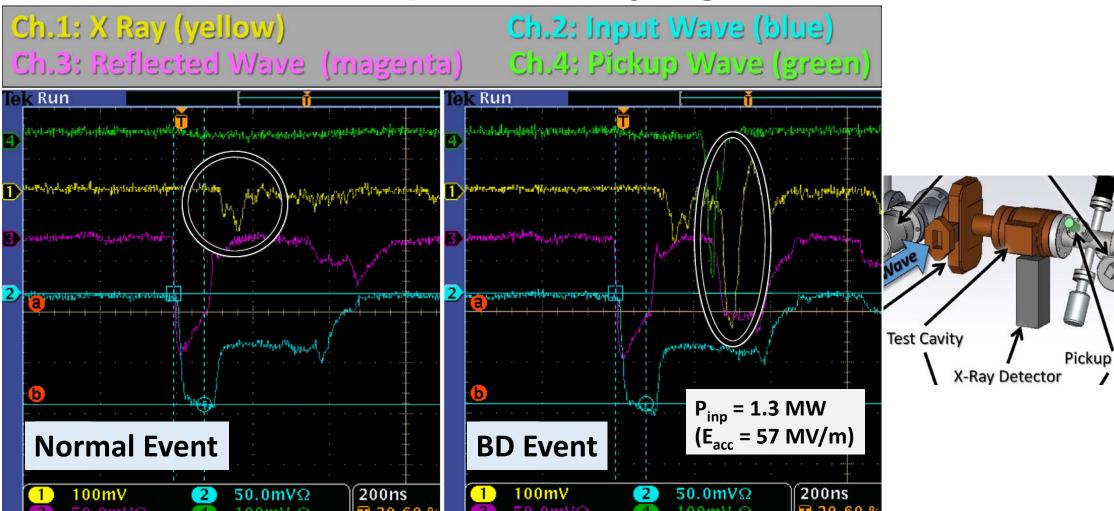


Standing Wave with the Maximum Field in the Central Test Cell

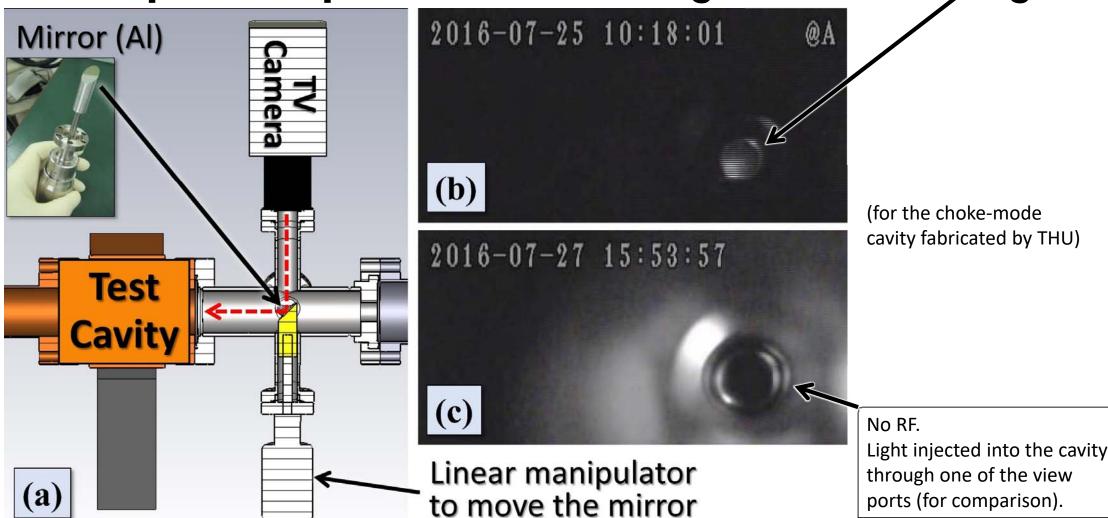


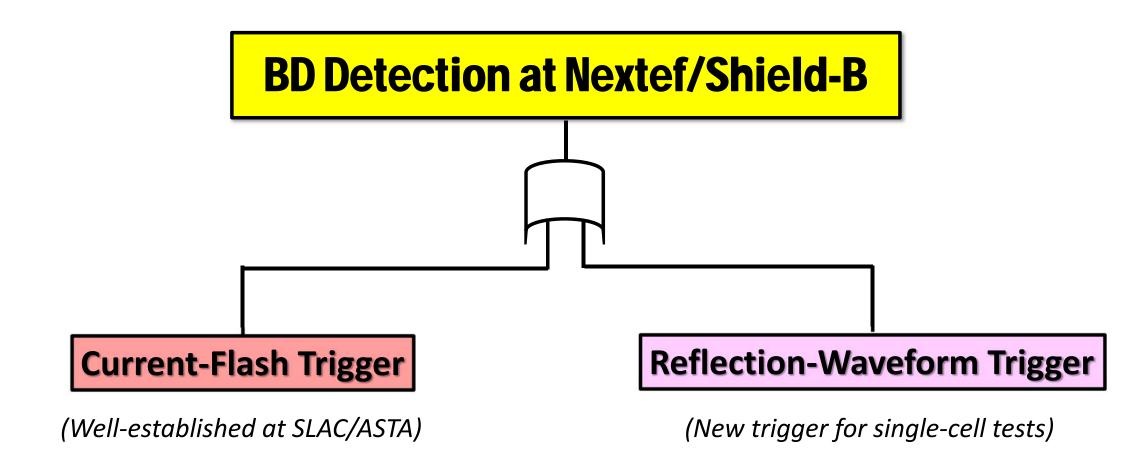


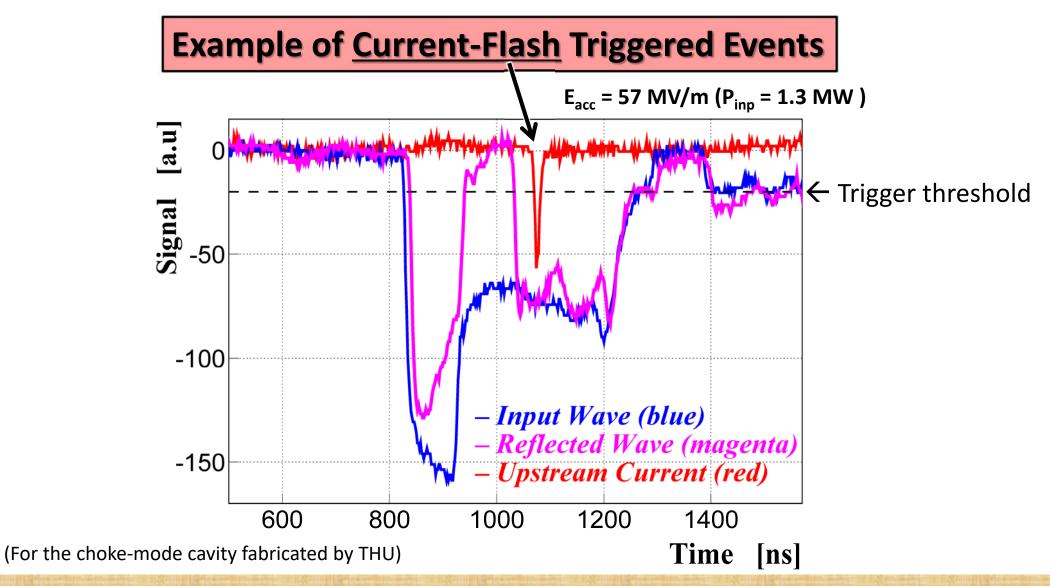
Examples of X-Ray Signals



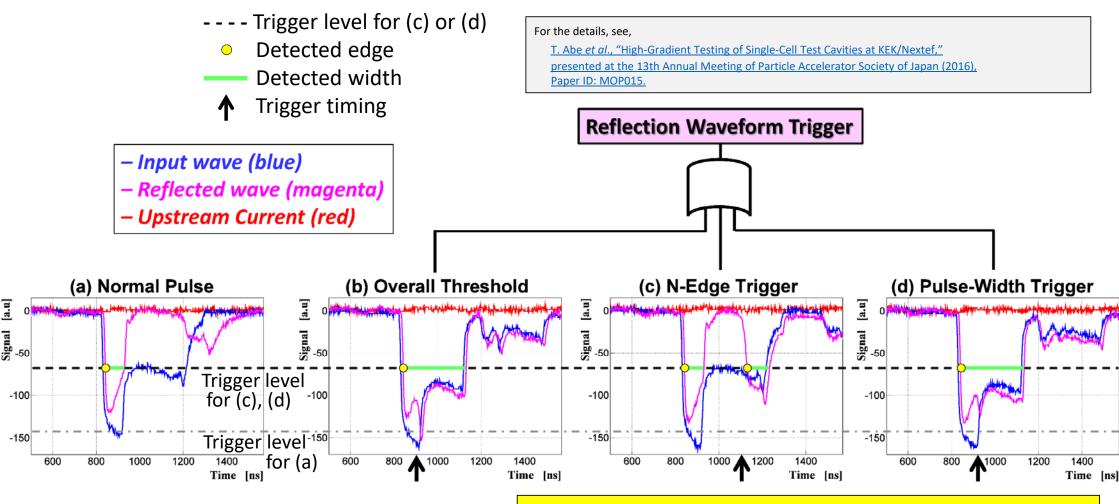
Example of Acquired TV Video Images with Discharge







Reflection-Waveform Trigger System



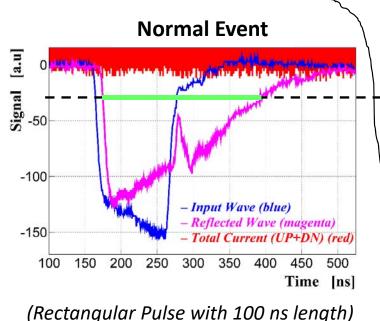
The trigger parameters have been continuously improved.

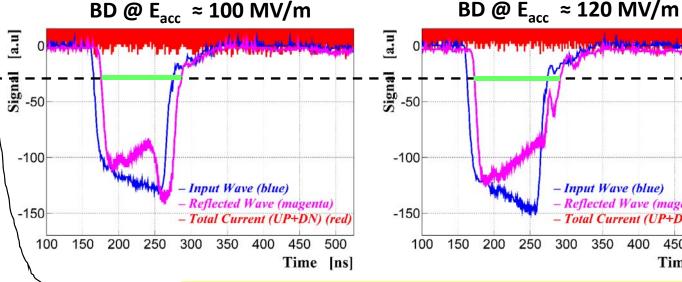
Examples of Waveform-Triggered Events with No Current Flash Detection

in the case of the undamped structure (fabricated by THU)

(Rectangular Pulse with 100 ns length)

If (the width at the trigger level) < 150 ns → Triggered





< 10% of the total BD events so far for the undamped structure

- ✓ Statistical analysis on-going
 - For the choke-mode structures, we observed many BD events with no current flash (→ next talk).

- Input Wave (blue)

- Reflected Wave (magenta)

350 400

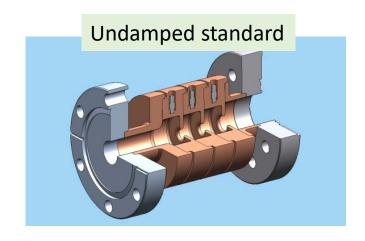
- Total Current (UP+DN) (red)

Time [ns]

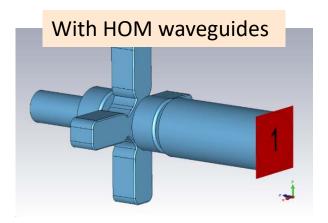
TEST STRUCTURES

Single Cell Structures to be tested at Shield-B

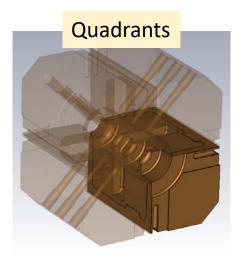
(Current list)



- With standard OFC (class1) and machined by turning
 - → For reference BDR
- With large grain
 - → To investigate grain-boundary effects



- Larger peak *H_{surf}*
- To compare with undamped ones

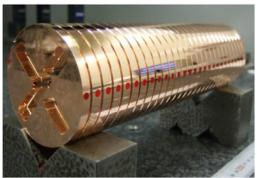


- To investigate the relation between surface current and bonding surface
- Etc...

Disk-type v.s. Quadrant(or Half)-type

Disk-type





A damped disk

Disks stacked and bonded

■ Advantages

- ✓ Machining by turning
- ✓ Very smooth surface (Ra = ~30 nm)
- ✓ Shallow machining damage (< 1 µm)

■ Disadvantages

- ✓ Ultra-high-precision machining of dozen of disks
 →Stack and bonding
- ✓ Great care
- ✓ Surface currents flow across disk-to-disk junctions.

Quadrant-type





A Quadrant

Three Quadrants

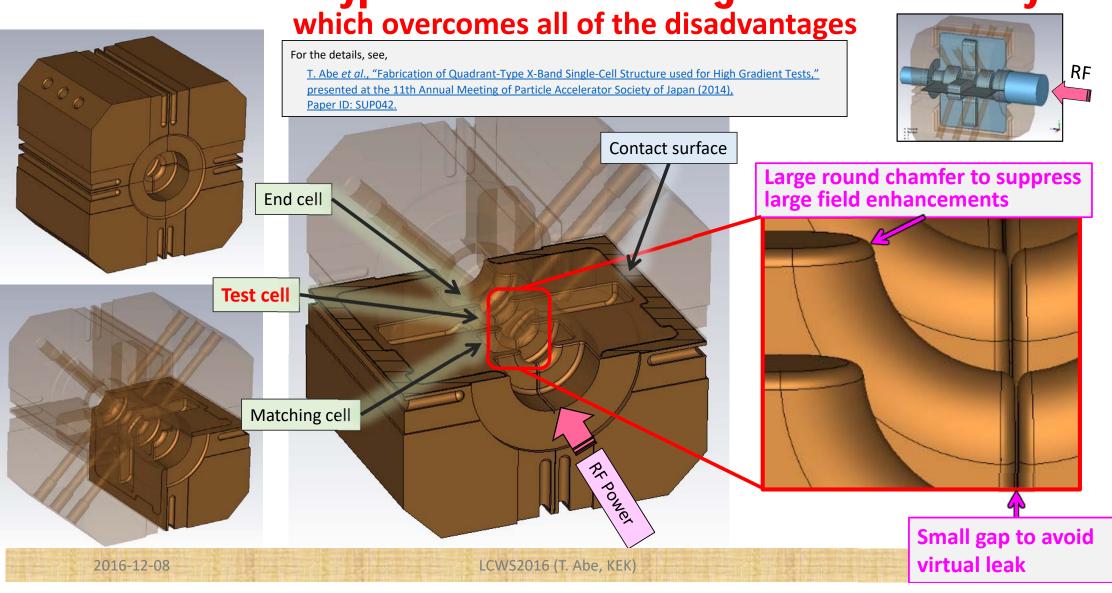
■ Advantages

- ✓ Surface currents do not flow across any disk-to-disk junction.
- ✓ Simple machining by five-axes milling machines
- ✓ Simple assembly process
 - → Significant cost reduction?

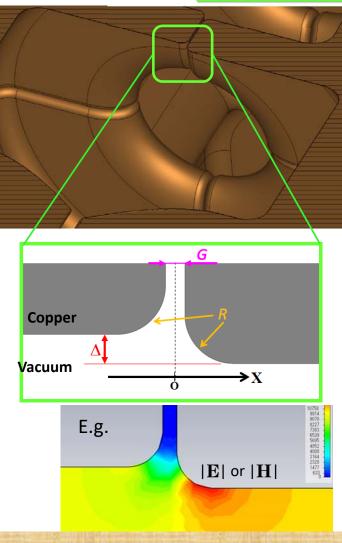
■ Disadvantages

- ✓ Not very smooth surface (Ra = $\sim 0.5 \mu m$)
- ✓ Deep machining damage (10 20 µm)
- √ Virtual leak from quadrant-to-quadrant junctions

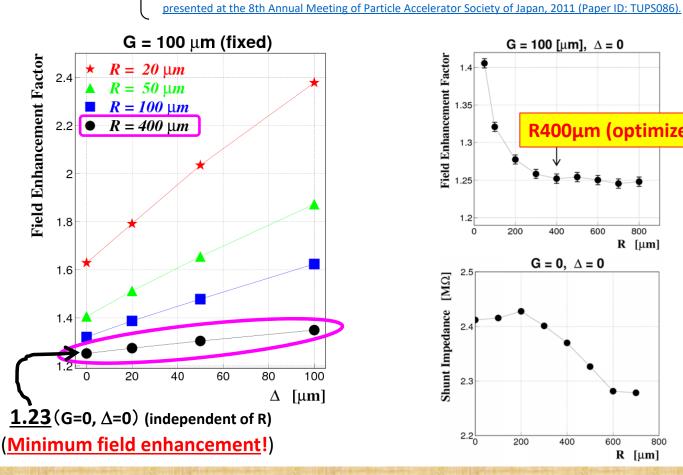
New Quadrant-type Structure as a Single-Cell Test Cavity

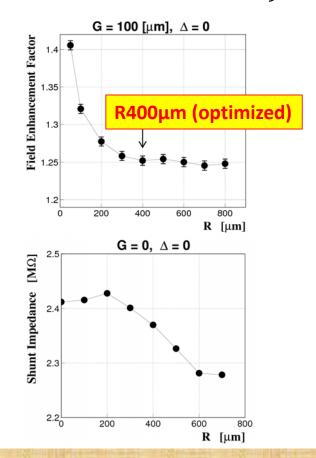


The large round chamber was optimized by a theoretical study on field enhancements due to misalignment of quadrants.

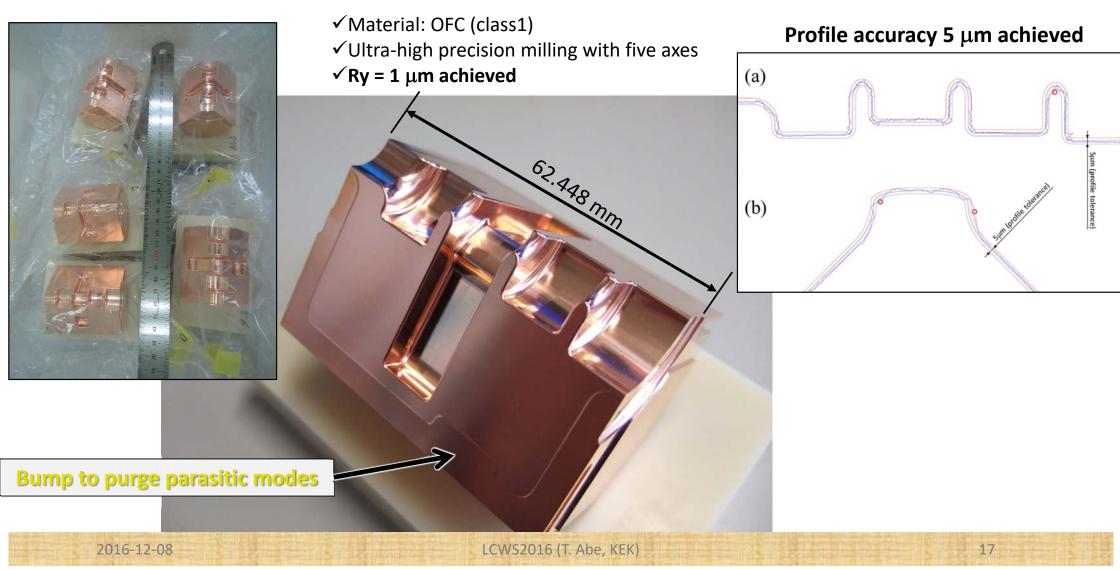


For more details, see T. Abe, "Study of Surface Field Enhancements due to Fine Structures,"





Delivered Quadrants for HG Test



Precise Assembly and EBW

(Electron Beam Welding)

T. Abe *et al.*, "Basic Study on High-Gradient Accelerating Structures at KEK/Nextef," in Proceedings of the 12th Annual Meeting of Particle Accelerator Society of Japan, August 2015 (Paper ID: WEP060).

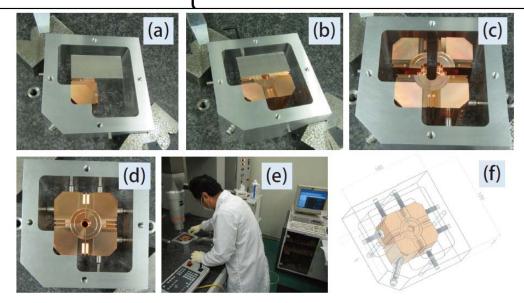


Figure 11: Precise assembly of the quadrants of the single-cell damped structure. (a) One quadrant fixed on an alignment frame. (b) Two quadrants aligned using an alignment block. (c) Replacing the alignment block by two quadrants. (d) After the last two quadrants aligned. (e) During the alignment of the last two quadrants using a CMM. (f) 3D drawing of the alignment frame including the quadrants.

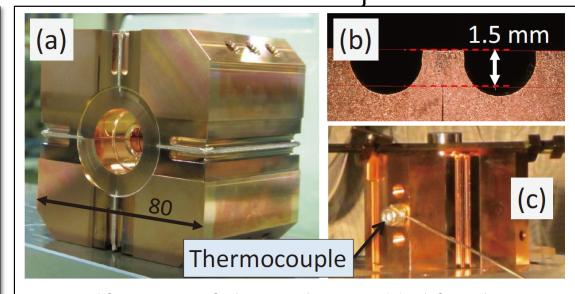


Figure 12: EBW of the quadrants. (a) After the EBW. (b) Welding penetration depth for the EBW conditions described in [13]. (c) A thermocouple is attached.



Frequency Measurement

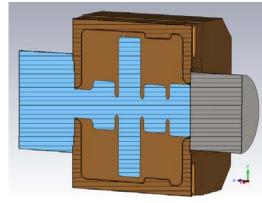
before and after the EBW

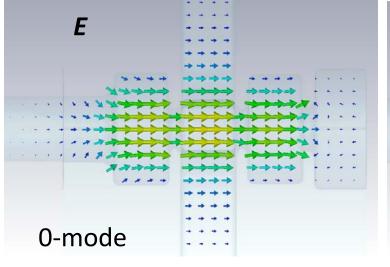
Pickup antenna

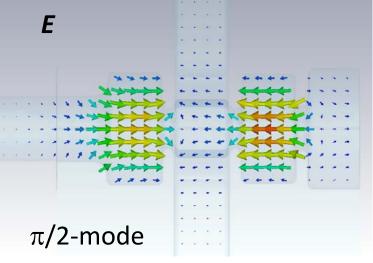


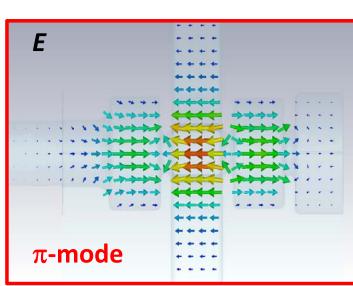
Measurements of the Mode Frequencies

Mode	After the EBW	Before the EBW	After - Before	
0	11.2872 GHz	11.2739 GHz	+13.3 MHz	
π/2	11.3362 GHz	11.3259 GHz	+10.3 MHz	
π (Accelerating mode)	11.4160 GHz	11.4104 GHz	+5.6 MHz ← w	ithin the scope of equency tuning

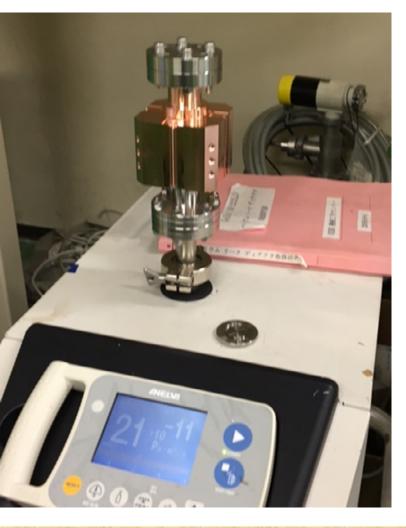








Beam Ports Brazed → No Vacuum Leak Confirmed → Cooling Pipes Brazed

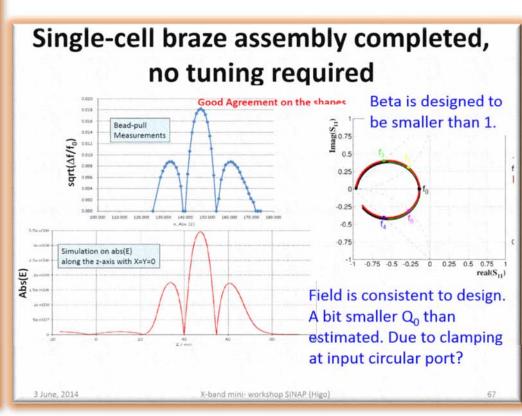




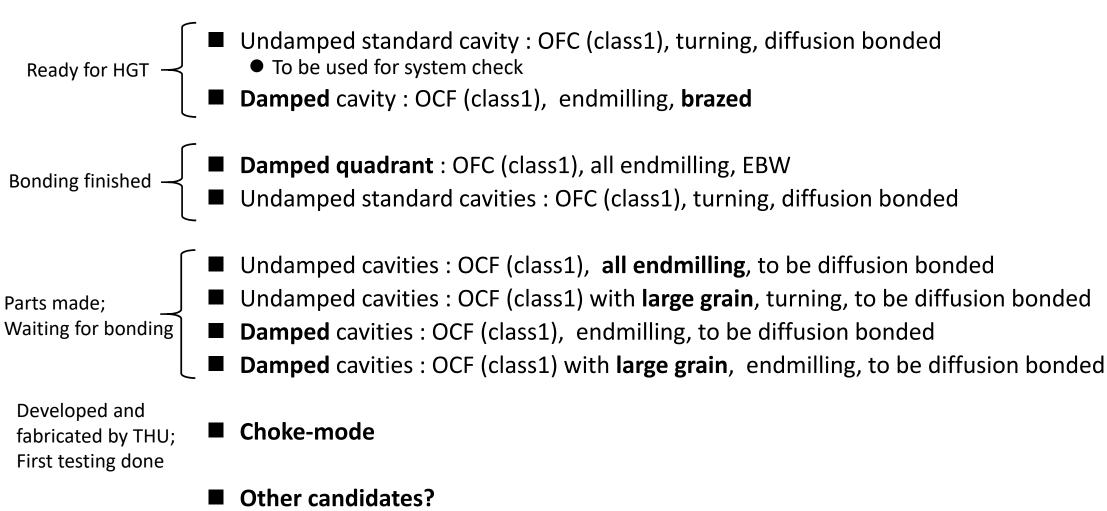
- → RF measurements and tuning
- → High-Gradient Test (next month?)

Example of Other Test Cavities

Single-cell SW braze-assembled **Brazing may fill** gap/corner in smooth manner Fabrication completed. and save Field profile is as designed against BD without tuning. Now ready for test. 3 June, 2014 X-band mini- workshop SINAP (Higo) 66



Structures to be tested at Nextef / Shield-B



Summary and Other Matters to be Considered

■ Basic study using X-band single-cell structures started at KEK/Nextef/Shield-B

- ✓ Max. $E_{acc} \approx 140$ MV/m ($P_{inp} \approx 20$ MW, $P_{kly-out} \approx 30$ MW, Width: 400 ns at max.)
- √ 1 [BD/hour] → BDR ≈ 4e-4 [BD/pulse/m] for L=13mm, 50 Hz rep. rate
 - → 100 Hz (or higher?) rep. rate to be tested at Shield-B
- ✓ Two choke-mode structures have been HG-tested.
 - > Refection-waveform trigger system detected many BD events with no current flash.
- ✓ Now, the undamped reference cavity (fabricated by THU) is being HG-tested.
- ✓ The trigger, control, DAQ systems are working fine with continuous improvements.

■Structures to be tested

- New quadrant-type waveguide-damped structure (next)
- Undamped reference, all turning or all endmilling
- Waveguide-damped structure fabricated by brazing
- Cavity made of OFC with large grain
- Others?

Thank you for your attention!